



IEEE SW Test Workshop
Semiconductor Wafer Test Workshop

June 12 to 15, 2011
San Diego, CA

Probe Card Cost Drivers from Architecture to Zero Defects

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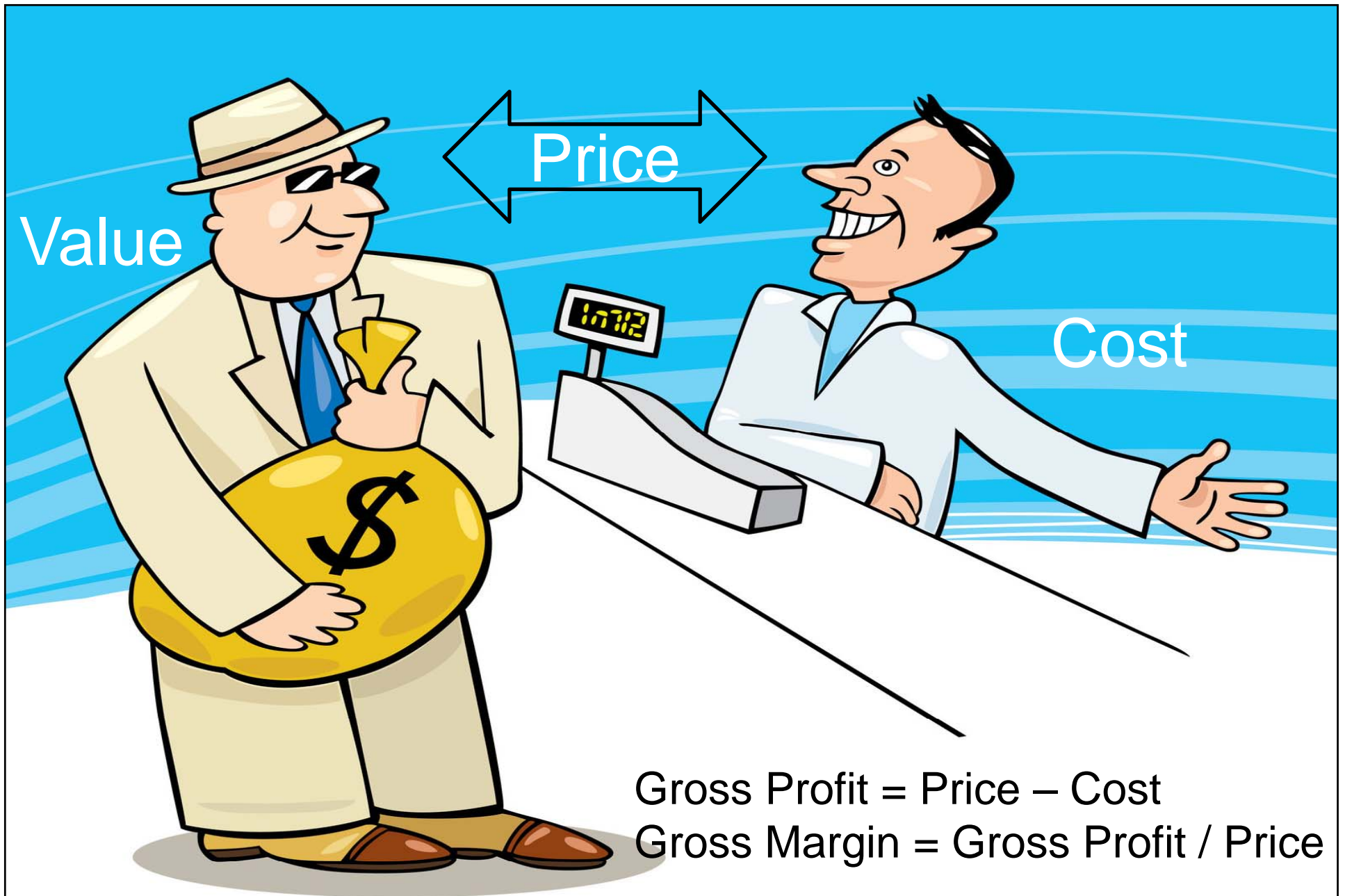
Feldman Engineering Corp.

Overview

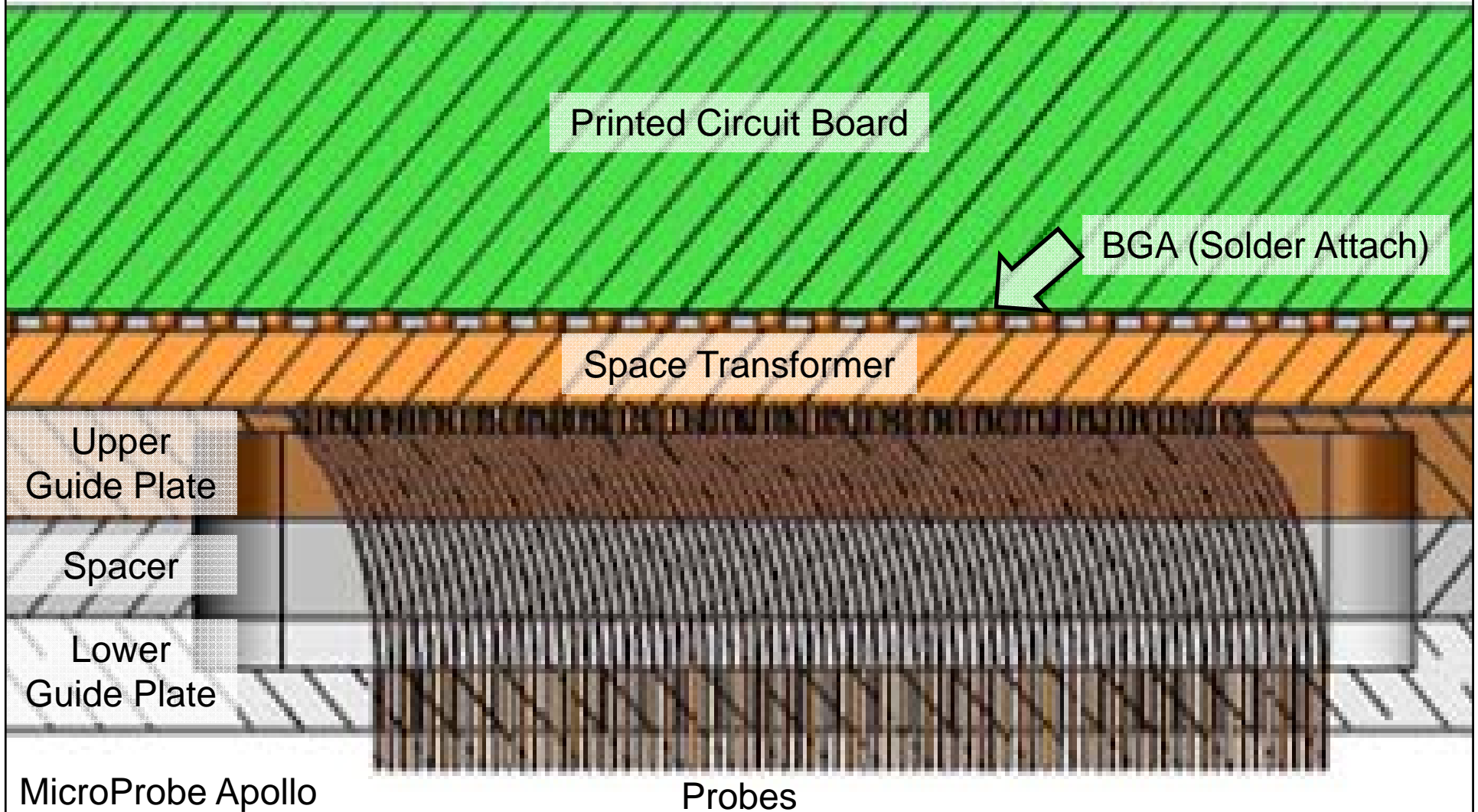
- **Cost, Price, & Cost Drivers**
- **Serial Processing – Drilling Example**
- **NRE**
- **Advanced Process Technology**
- **Profitless Prosperity**
- **Cost Savings**
- **Summary**

Note: price/cost examples are approximate and from multiple vendors not necessarily those identified or shown.





Vertical Probe Head

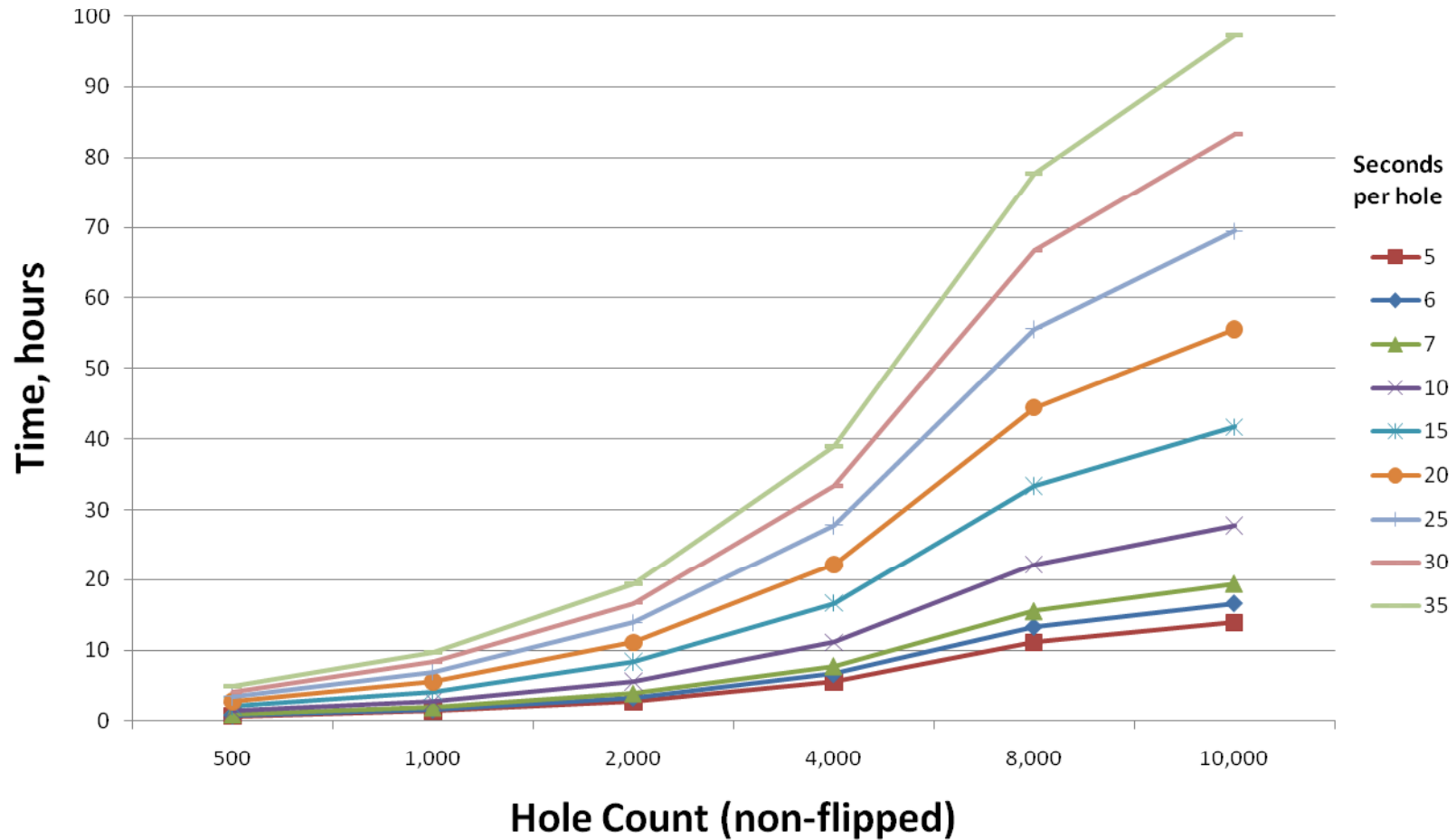




Machine Shop
Cost Drivers
Programming
Material
Setup Time
Run Time
Inspection
Yield



Drill Time

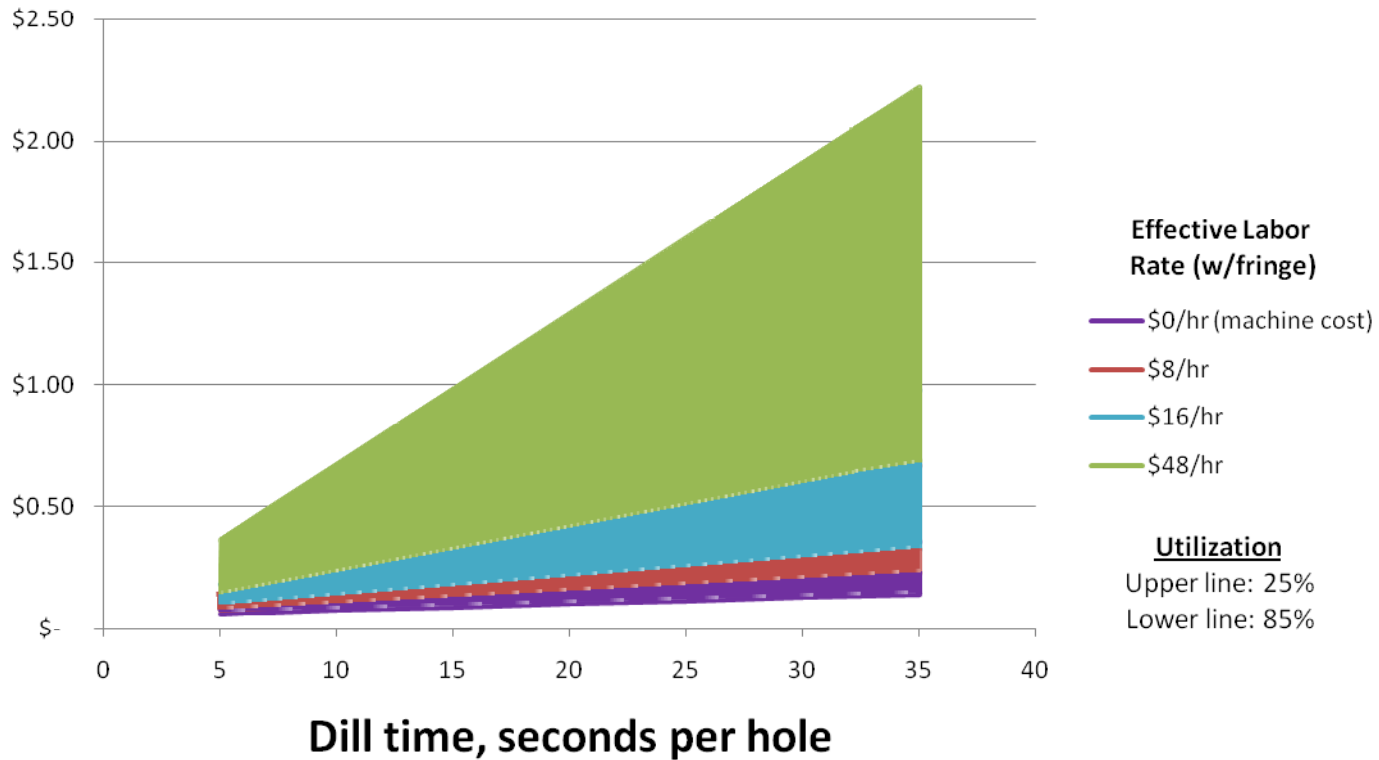


Don't bother...

"Ferrari"



Cost Per Drill Hole



Machine Cost	\$300,000
Annual Maintenance	7%
Useful Life	7 years
Total Cost	\$447,000
Facilities Annual Cost	\$35,000
Total Annual Cost	\$68,857

<u>Machine Cost</u>	
25% utilization	\$31.44 /hr
85% utilization	\$9.25 /hr
Tooling per hole	\$ 0.05

Don't bother...

"Ferrari"



Make vs. Buy



Utilization
Lead Time
Quality
Fixed vs. Variable Cost
Cost (Make) vs. Price (Buy)

Non Recurring Engineering Expense

Architecture	Design	Tester	Customer
R&D	NRE	NRE	NRE
Design Input	X		X
Probes			?
Guide Plates	X		
Space Transformer	X		
Interposer	?		
PCB Design	X (External?)	X	?
PCB Fab	External	?	?
Mechanical H/W	?	X	?
Electronics	?	?	?
Metrology	X	X	?
Packaging		X	?

Outgoing Metrology



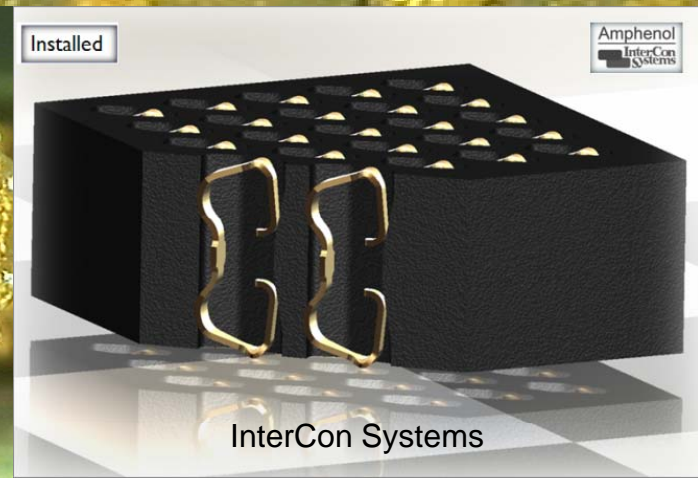
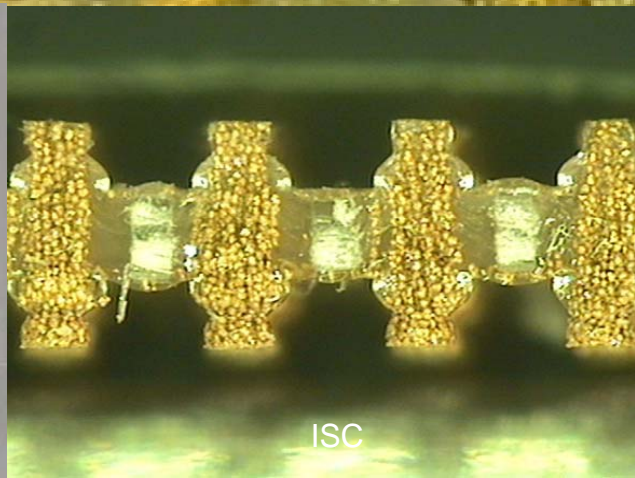
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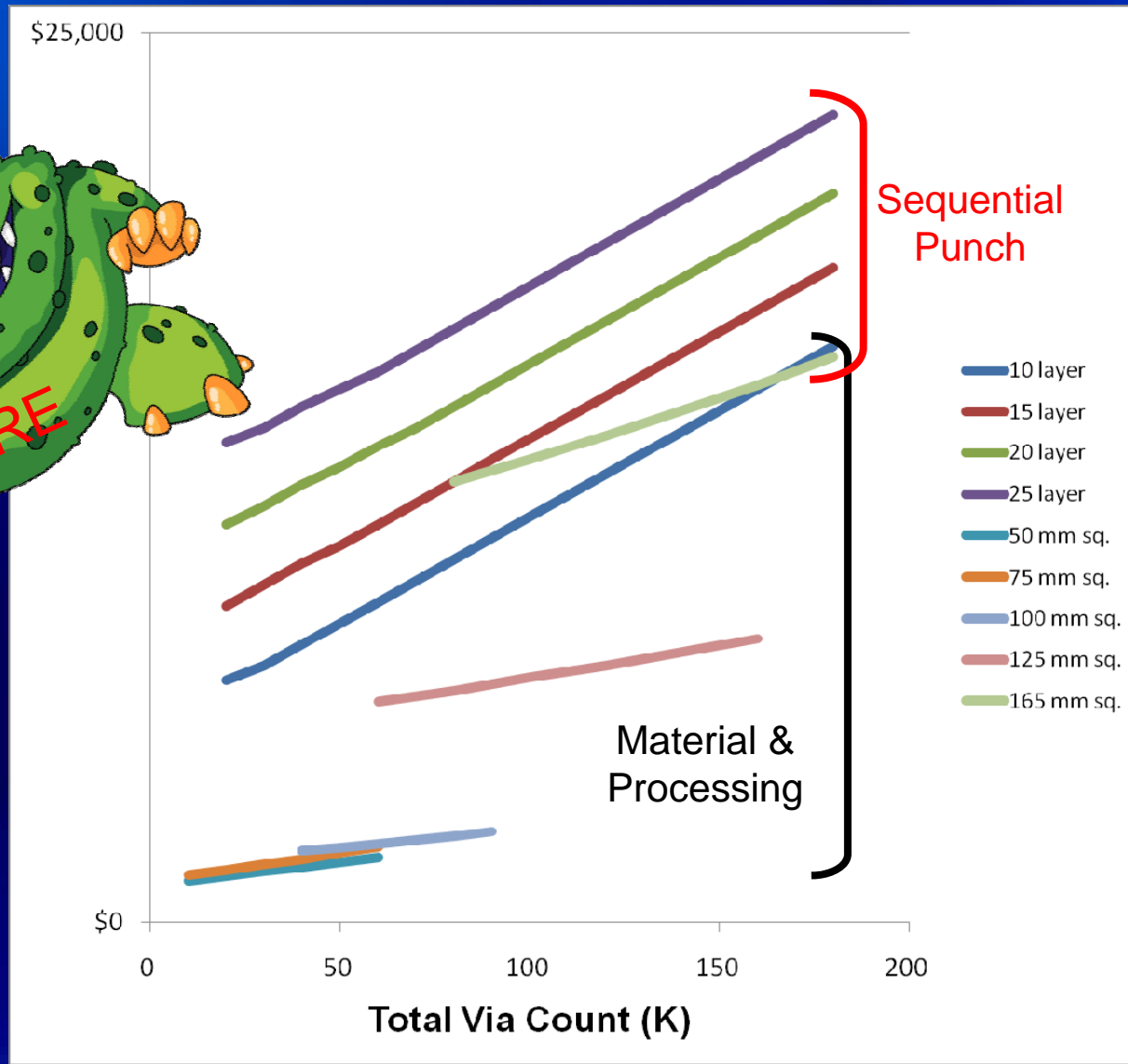
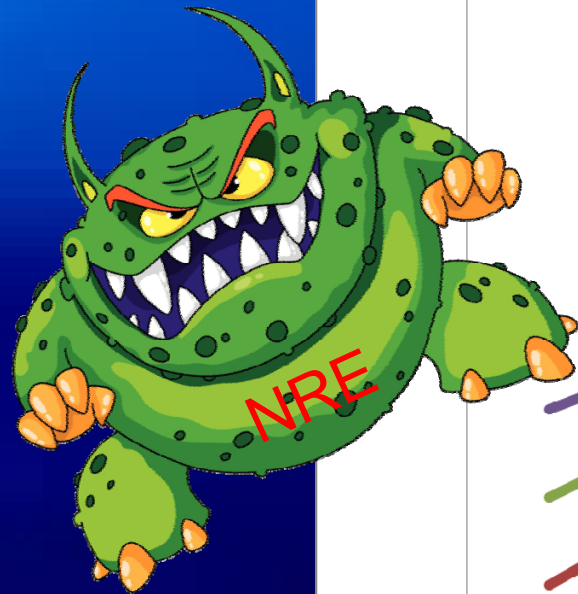
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Interposers

		Spring Pin	Elastomeric	Molded Frame
Small Area	NRE	\$.5 - 1 K	\$2 - 3 K	\$20 - 30 K
	\$ / contact	\$1 - 10	\$.50 - .60	< \$.20 - .40
Large Area (1/4 wafer +)	NRE		\$10 - 15 K	\$100 - 150 K
	\$ / contact		\$.40 - .50	< \$.10 - .20



Space Transformers



Advanced Process Technology

Cost Drivers

Process Steps

Masks

Substrates

Material

Active Area

Yield

Defect Density

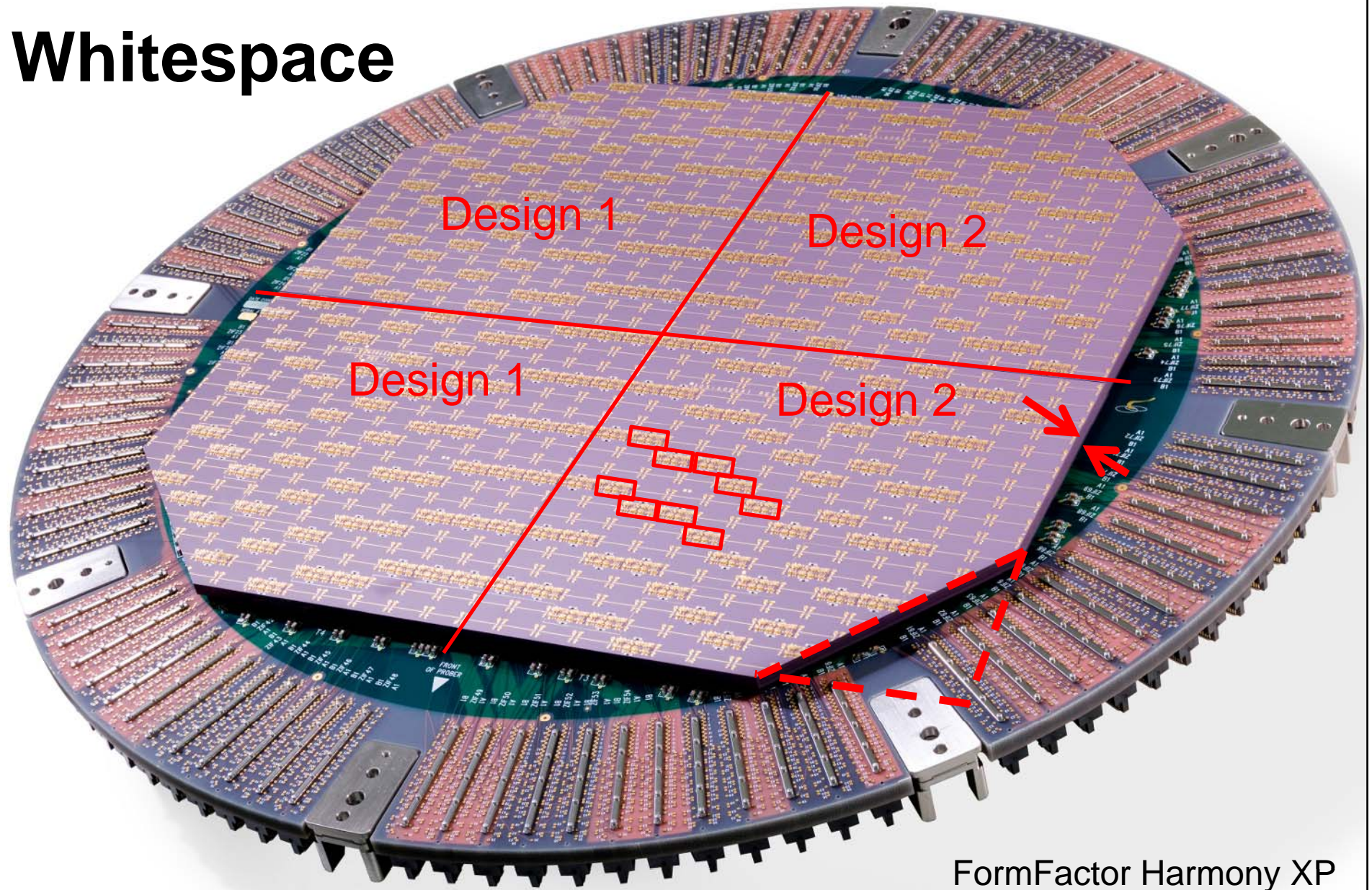
Layers

Equipment

Rework / Repair

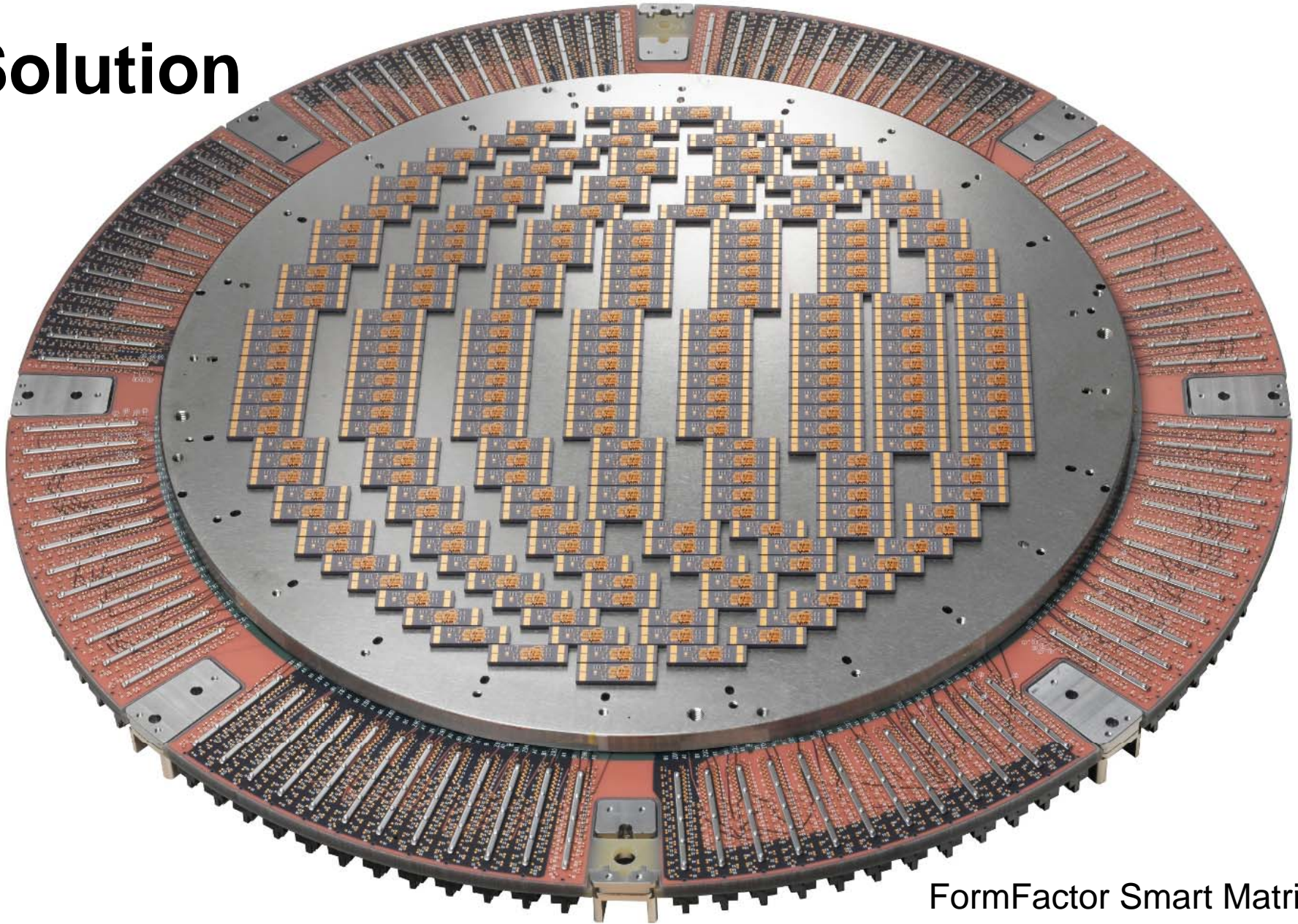


Whitespace



FormFactor Harmony XP

Solution



FormFactor Smart Matrix

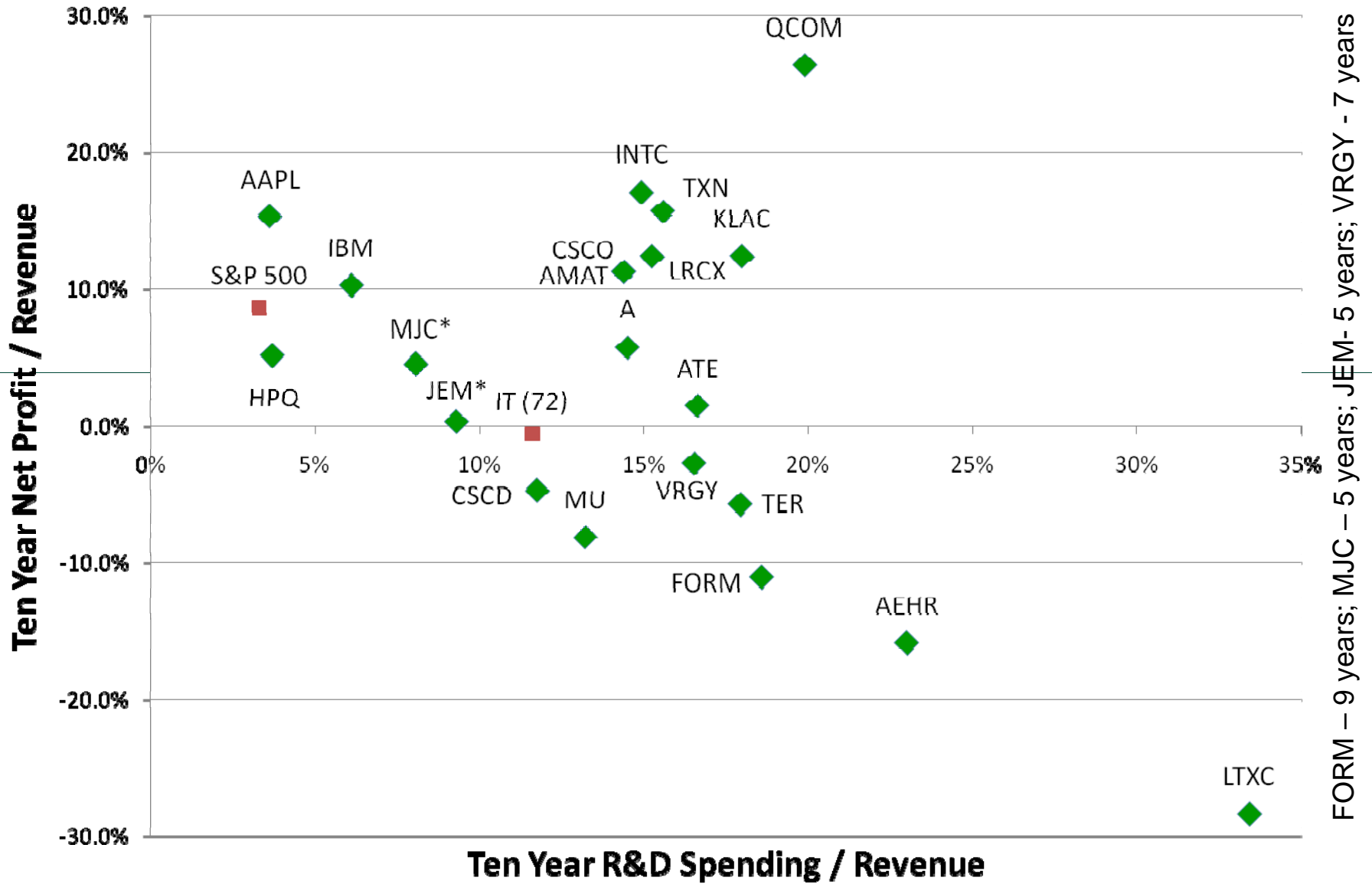


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Ten Year Profitability



FORM – 9 years; MJC – 5 years; JEM – 5 years; VRGY – 7 years



Costs Savings

STANDARDS

Input Data Formats

Probe Depth

Testhead Configurations

Specifications



Summary

- **Understand true cost of architectures**
 - Beware of NRE
 - New architectures needed for cost reductions
- **Maintain sufficient Gross Margin**
 - Company health
 - Funding for R&D
- **Honest supplier – customer partnerships**



Acknowledgments

- Amphenol InterCon Systems
- BucklingBeam
- FormFactor
- ISC
- Kern
- Robin McAdams
- MicroProbe
- Sergio Perez
- SV Probe
- Frank Swiatowiec



Thank You!

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